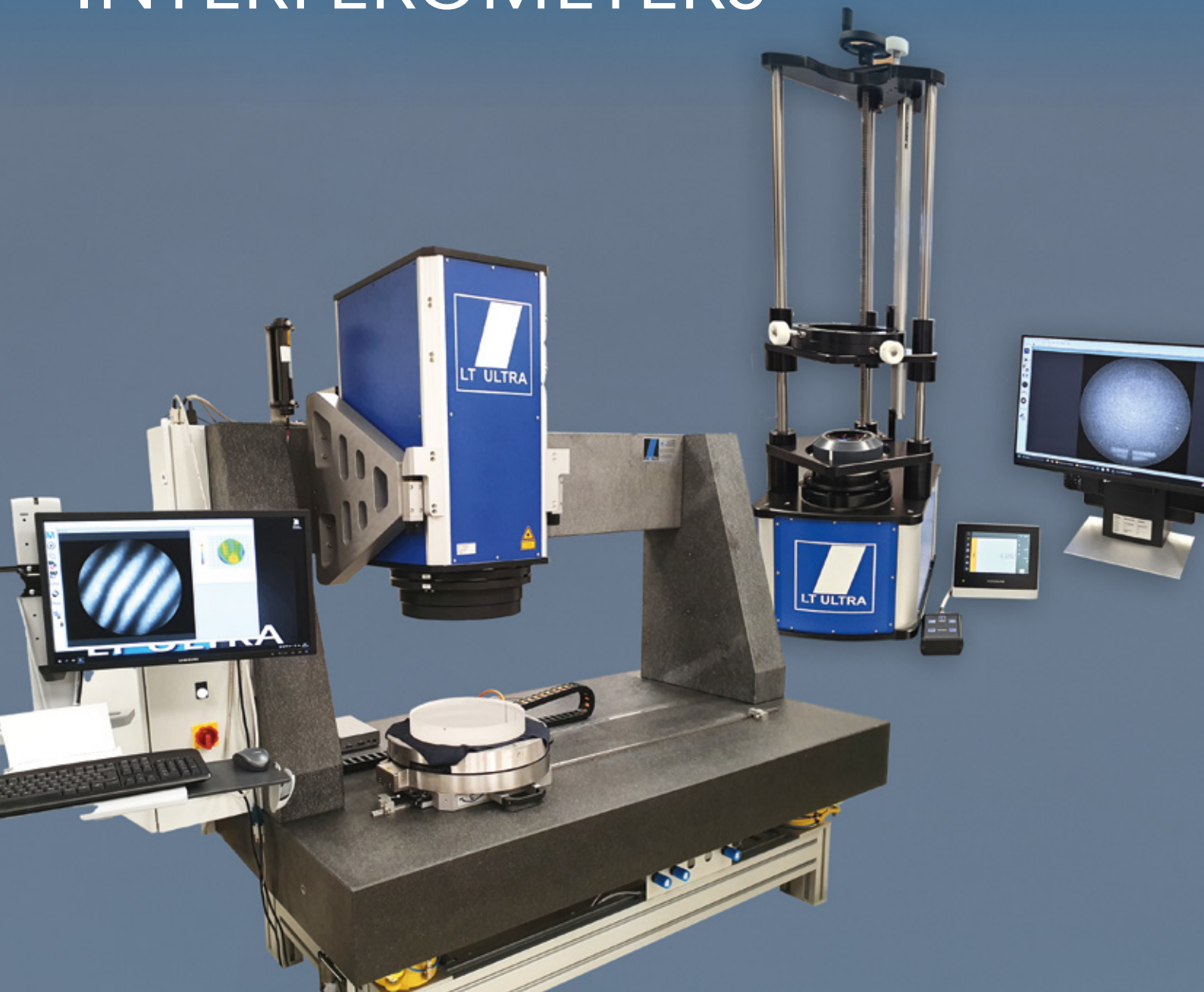


ULTRA-PRECISION MEASUREMENT SYSTEMS INTERFEROMETERS



Top Features: Stitching · Multi-aperture measurement · Auto alignment · Additional axes · In-line measurement · Customized · Robust – measuring under challenging conditions is no problem



Oblique incidence interferometer for specimens >> 1 m

Extensive Accessory Options

Our wide range of accessory options helps you achieve the best possible results:

- Automatic evaluation software
- Piezo phase-shifting unit
- Wavelength shifting
- Various objectives
- Flat / spherical / aspherical
- Measurement system for ultra-precise radius determination
- Higher resolution
- Granite portal structure
- Air-bearing specimen stages
- Vibration damping systems (active/passive)
- Software features:
 - Live image
 - Stitching
 - Multi-aperture evaluation
 - Auto alignment
 - Automatic report generation
 - 2D and 3D graphics
 - Various measurement visualizations
 - Calibration

These are just some of the most commonly used options. Contact us and our experts will work with you to create the perfect package for your measurement application.

Ultra-Precision Measurement Systems

Fizeau interferometers have been a core and essential part of our comprehensive portfolio since the company was founded over 30 years ago — and they continue to evolve.

Probably the only truly industrial-grade interferometer

If your requirements go beyond our standard models, we are happy to develop customized solutions for you.

Highest Precision and Versatility

Form deviations are measured within seconds with accuracies up to $\lambda/10$. While flat workpieces are the most common application, spheres, aspheres, and freeform surfaces can also be measured easily using the appropriate objectives or CGHs.

Proven Across Numerous Industries

Our interferometers are already successfully used in the following sectors:

- OEM
- Optics and Laser Technology
- Medical Technology
- Semiconductor Industry
- Fundamental Research
- Metrology
- Aerospace

Unique Design

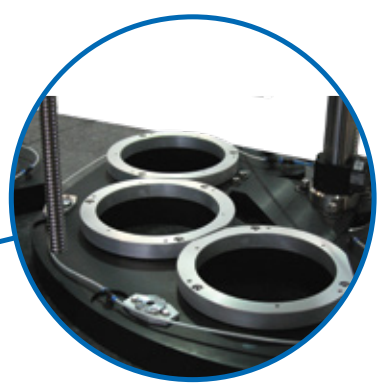
Our interferometers are characterized by the following features:

- High-precision measurements even under difficult conditions
- Vertical or horizontal configuration
- HeNe laser / stabilized diode
- Accuracies up to $\lambda/10$ (better on request)
- HR-coated / uncoated reference
- 1800 x 1800 pixel chip
- Alignment assistance
- Zoom

Base Models: 4" / 6" / 12"

Our base models are available in various sizes, either as:

- Benchtop device
- Stand-alone unit
- Measurement station
- Integrated into UP manufacturing machines
- Integrated into measurement machines



6" double measuring cascade with air-bearing lens changer

